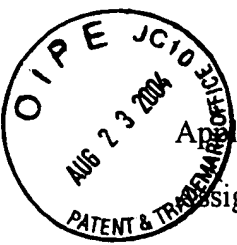


*Handwritten initials: FW/B*



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehdi Vaez-Iravani et al.  
Assignee: KLA-Tencor Corporation  
Title: Sample Inspection System  
Application No.: 10/671,261 Filing Date: Sept. 24, 2003  
Examiner: Pham, Hoa Q. Group Art Unit: 2877  
Docket No.: TNCR.152US8 Conf. No.: 6611

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant calls the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

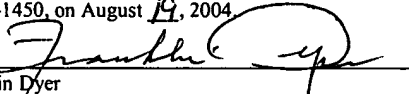
Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This application has a filing date after June 30, 2003. Copies of the U.S. Patent(s) and U.S. Published Patent Application(s) documents listed on the accompanying Form PTO-1449 are not enclosed.

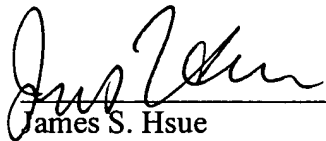
This information disclosure statement is submitted under 37 C.F.R. § 1.97(c). A check including \$180.00 for the information disclosure statement fee under 37 C.F.R. § 1.17(p), is

08/25/2004 WABDELRI 00000013 10671261 180.00 DP 01 FC:1806

enclosed. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

<p align="center"><u>Certificate of Mailing Under 37 CFR 1.8</u></p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope address to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on August <u>19</u>, 2004.</p> <p> _____ Franklin Dyer</p>
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Respectfully submitted,

	<u>8/19/04</u>
James S. Hsue	Date
Reg. No. 29,545	

U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)				TNCR.152US8		10/671,261	
				Applicant(s)		Conf. No.	
				M. Vaez-Iravani et al.		6611	
				Filing Date		Group	
				September 24, 2003		2877	

U.S. Patent Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,558,949	12/85	Uehara et al.			
	AB	4,893,932	1/1990	Knollenberg			
	AC	5,058,982	10/1991	Katzir			
	AD	5,712,701	1/98	Dementi et al.			
	AE	5,929,983	7/99	Lu			
	AF	6,118,525	9/00	Fossey et al.			
	AG	6,169,601	1/01	Eremin et al.			

U.S. Published Patent Application Documents							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AH	WO97/33158	9/1997	International			X	
	AI	EP0624787	11/1994	Europe			X	
	AJ	DE4123916	1/1992	German				X
	AK	WO97/12226	4/1997	International			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
AL	"Surface Inspection System for Estimation of Wafer," Y. Yatsugake et al., <i>Hitachi Electronics Engineering Technical Report</i> , Vol. 11, January 1996, pp. 21-26	
AM	Figure, Hitachi Electronics Engineering Co., Ltd., presented by Etsuro Morita of Mitsubishi Materials Silicon Corp. in a presentation entitled "Exploration of COP and COP Defect Crystal Originated 'Particles'." at the 6 <sup>th</sup> International Workshop on 300 Millimeter Wafers on 12/5/1996 in Makuhari, Japan	
AN	Partial European Search Report dated October 18, 2000	

Examiner	Date Considered
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark	Atty. Docket No.	Application No.
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	Applicant(s)	Conf. No.
(Use several sheets if necessary)	M. Vaez-Iravani et al.	6611
	Filing Date	Group
	September 24, 2003	2877

## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AO	4,589,773	5/86	Ido et al.			
	AP	4,740,079	04/88	Koizumi et al.			
	AQ	4,966,457	10/90	Hayano et al.			
	AR	5,125,741	6/92	Okada et al.			
	AS	5,189,481	2/93	Jann et al.			
	AT	5,245,403	9/93	Kato et al.			
	AU	5,465,145	11/95	Nakashige et al.			

## U.S. Published Patent Application Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

## Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AV	WO96/15354	9/25/96	International			X	
	AW	WO97/04134	3/5/97	International			X	
	AX	WO99/14575	3/99	International			X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AY	Search Report Corresponding to PCT Application No. PCT/US98/19564 issued by the International Patent Office on February 8, 1999.

Examiner

Date Considered

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	Filing Date	Group
	September 24, 2003	2877

## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AZ	4,395,126	7/83	Kramer			
	BA	4,449,818	5/84	Yamaguchi			
	BB	4,540,286	9/85	Satake et al.			
	BC	4,598,997	7/86	Steigmeier et al.			
	BD	4,669,875	6/87	Shiba et al.			
	BE	4,794,265	12/27/88	Quackenbos et al.			
	BF	4,861,164	8/89	West			
	BG	4,898,471	2/6/90	Stonestrom et al.			
	BH	RE: 33,956	6/92	Line et al.			
	BI	5,155,372	10/92	Bowen et al.			
	BJ	5,245,403	9/93	Kato et al.			
	BK	5,463,459	10/95	Morioka et al.			
	BL	5,389,794	2/14/1995	Allen et al.			
	BM	5,486,919	1/96	Tsuji et al.			
	BN	5,530,550	6/25/96	Nikoonahad et al.			
	BO	5,672,885	9/97	Allen et al.			
	BP	5,672,885	9/97	Allen et al.			
	BQ	5,940,175	8/99	Sun			
	BR	6,084,664	7/00	Matsumoto et al.			
	BS	6,201,601	3/01	Vaez-Iravani et al.			

Examiner

Date Considered

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